TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (Ultra-High-Speed U-MOSIII)

# **TPC8213-H**

High-Efficiency DC / DC Converter Applications

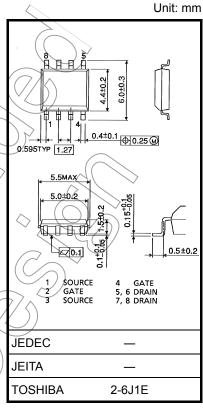
Notebook PC Applications

Portable-Equipment Applications

- Small footprint due to small and thin package
- · High-speed switching
- Small gate charge: Q<sub>SW</sub> = 2.9 nC (typ.)
- Low drain-source ON-resistance:  $R_{DS (ON)} = 40 \text{ m}\Omega \text{ (typ.)}$
- High forward transfer admittance: |Y<sub>fS</sub>| =11 S (typ.)
- Low leakage current: I<sub>DSS</sub> = 10 μA (max) (V<sub>DS</sub> = 60 V)
- Enhancement mode:  $V_{th}$  = 1.1 to 2.3 V ( $V_{DS}$  = 10 V,  $I_D$  = 1 mA)

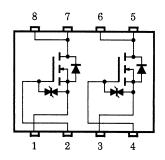
### Absolute Maximum Ratings (Ta = 25°C)

Chai	racteristic	Symbol	Rating	Unit
Drain-source vol	tage	$V_{DSS}$	60	V
Drain-gate voltag	ge (R <sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub> <	60	/y
Gate-source vol	tage	V <sub>GSS</sub>	±20	<b>Y</b>
Drain current	D C (Note 1)	ID( (	5	A
Diam current	Pulse (Note 1)	₽ A	20	^
Drain power dissipation	Single-device operation (Note 3a)	$\left( R_{\mathbb{D}(1)} \right)$	1.5	
(t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	PD (2)	1.1	W
Drain power dissipation	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.75	
(t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	P <sub>D</sub> (2)	0.45	W
Single-pulse avalanche energy (Note 4)		Eas	90	mJ
Avalanche currer	ît.	< JAR	5	Α
Repetitive avalanche energy (Note 2a, Note 3b, Note 5)		EAR	0.087	mJ
Channel tempera	ture (	Teh	150	°C
Storage tempera	ture range	T <sub>stg</sub>	-55~150	°C



Weight: 0.085 g (typ.)

### **Circuit Configuration**



Note: For Notes 1 to 5, refer to the next page.

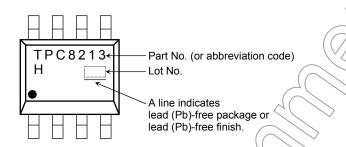
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

#### **Thermal Characteristics**

Characteristic	Symbol	Max	Unit	
The arrest resistance about the cushicut	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	83.3	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	114	°C/W
Thermal registeres, abancol to embient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	167	
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	278	

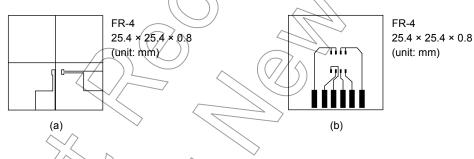
## Marking



Note 1: The channel temperature should not exceed 150°C during use

#### Note 2:

- a) Device mounted on a glass-epoxy board (a)
- b) Device mounted on a glass-epoxy board (b)



Note 3:

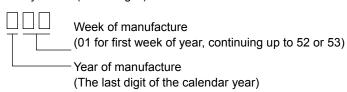
- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)

Note 4:  $V_{DD}$  = 24 V,  $T_{ch}$  = 25°C (Initial), L = 5 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 5.0 A

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: • on the lower left of the marking indicates Pin 1.

\* Weekly code: (Three digits)



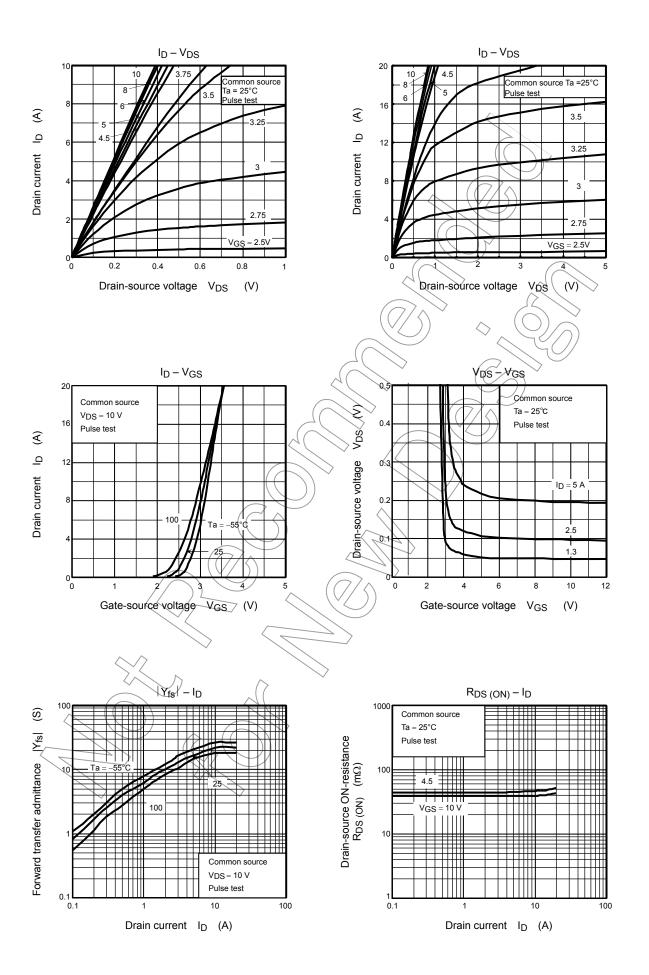
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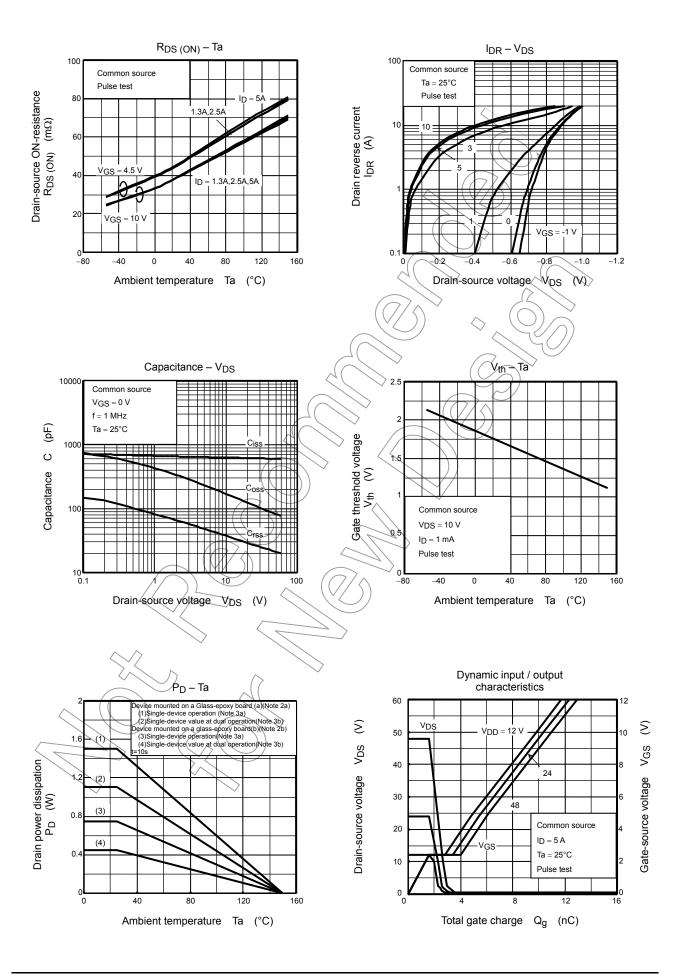
## Electrical Characteristics (Ta = 25°C)

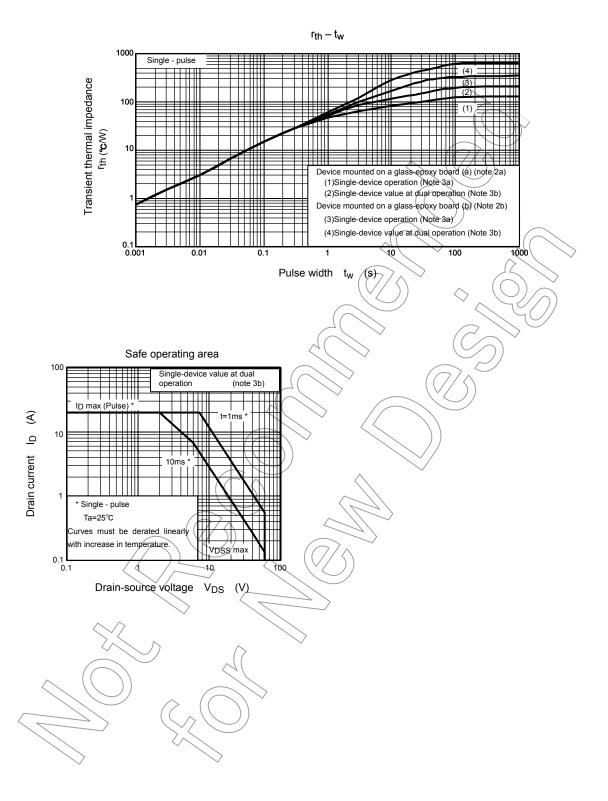
Chara	cteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain cutoff curr	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V	_	_	10	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_		V
Drain-source breakdown voltage		V <sub>(BR)DSX</sub>	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	45	_	-	
Gate threshold v	/oltage	$V_{th}$	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	\11	) >-	2.3	V
Drain-source O	N-resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 2.5 A		45	56	mΩ
Drain-source ON-resistance		R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V , I <sub>D</sub> = 2.5 A		40	50	11152
Forward transfer	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V , I <sub>D</sub> = 2.5 A	5.5	11	_	S
Input capacitano	ce	C <sub>iss</sub>			625		
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		35	/	pF
Output capacitance		C <sub>oss</sub>			175	$\searrow$	
Switching time	Rise time	t <sub>r</sub>	V <sub>GS</sub> <sup>10</sup> V	(	4	> _	
	Turn-on time	t <sub>on</sub>			10	_	
	Fall time	t <sub>f</sub>			2	1	
	Turn-off time	t <sub>off</sub>	Duty ≨ 1%, t <sub>w</sub> = 10 μs	_	19	_	
Total gate charge (gate-source plus gate-drain) (Note 7)		$Q_g$	$V_{DD} = 48 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		11		
			$V_{DD} \approx 48 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 5 \text{ A}$		6		
Gate-source charge 1		Q <sub>gs1</sub>		_	1.6	_	nC
Gate-drain ("Miller") charge		Qgd	V <sub>DD</sub> ≈ 48 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A	_	2.4	_	
Gate switch charge		Qsw		_	2.9	_	

## Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current Pulse (Note 1)	I <sub>DRP</sub>	<u> </u>	_	_	20	Α
Forward voltage (diode)	/V <sub>DSF</sub>	I <sub>DR</sub> = 5 A, V <sub>GS</sub> = 0 V		_	-1.2	V







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